

Search Notes

Application/Control No.

10/516,824

Examiner

Phil J. Kauffman

Applicant(s)/Patent under
Reexamination

OTAGURO, TETSUNORI

Art Unit

3652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
414/217 US only	7/28/2006	PJK
wafer and manufacture and FOUP S17 JPO DERWENT	7/28/2006	PJK
wafer and manufacture and SMIF S18 JPO DERWENT	7/28/2006	PJK
wafer and manufacture and container S19 JPO DERWENT	7/28/2006	PJK
(container or smif or FOUP) and manufacture and system and ceiling JPO DERWENT	7/28/2006	PJK
(container or smif or FOUP) and manufacture and system and (overhead or "over head") JPO DERWENT	7/28/2006	pjk
East search attached		PJK